

<b>Search Notes</b> 	<b>Application/Control No.</b>  09/990,717	<b>Applicant(s)/Patent under Reexamination</b>  WIENER ET AL.
	<b>Examiner</b>  Md S. Elahee	<b>Art Unit</b>  2614

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner